

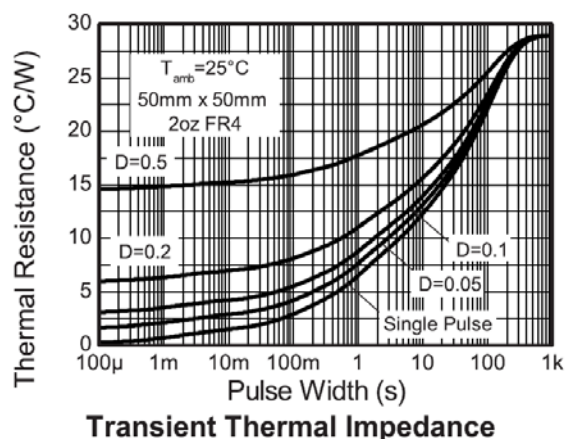
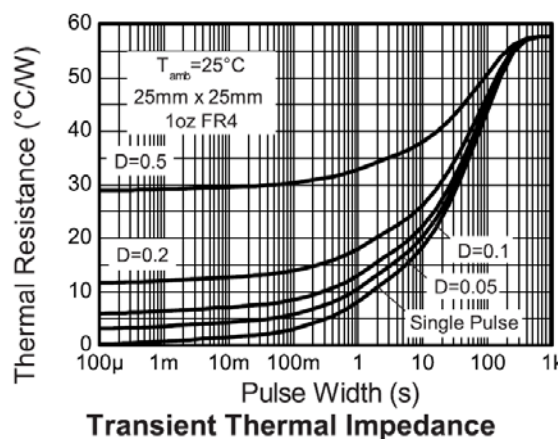
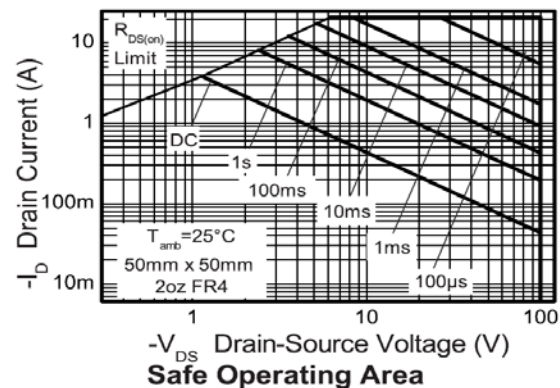
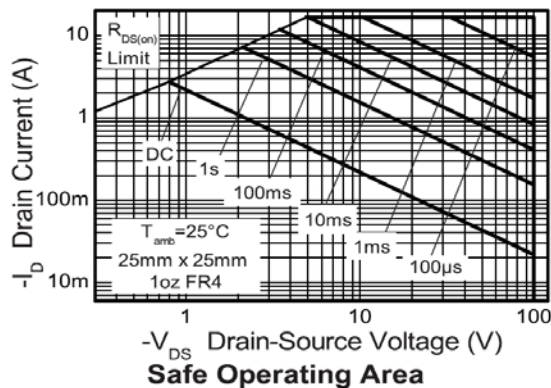
Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

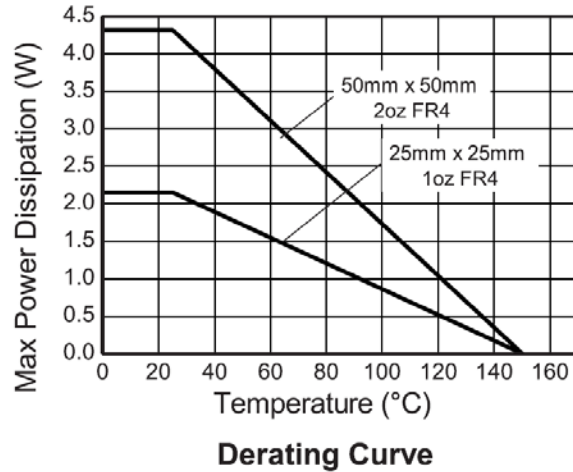
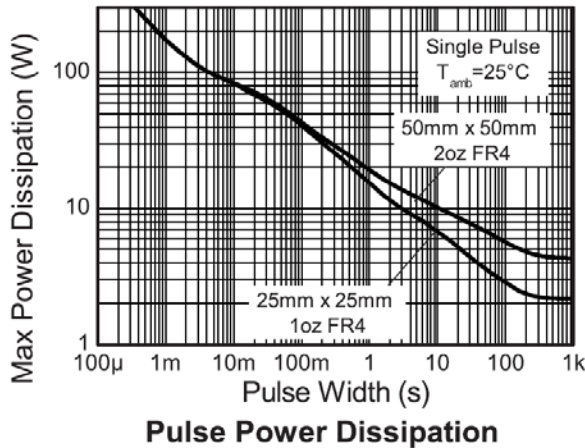
Characteristic	Symbol	Value	Units
Drain-Source Voltage	V_{DS}	-100	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	$T_A = +25^\circ\text{C}$ (Note 6)	A
		$T_A = +70^\circ\text{C}$ (Note 6)	
		$T_A = +25^\circ\text{C}$ (Note 5)	
Pulsed Drain Current (Note 7)	I_{DM}	-21.1	A
Continuous Source Current (Body Diode) (Note 6)	I_S	-10	A
Pulsed Source Current (Body Diode) (Note 7)	I_{SM}	-21.1	A

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5) Linear Derating Factor	P_D	4.3	W
		34.4	mW/ $^\circ\text{C}$
		10.2	W
		81.3	mW/ $^\circ\text{C}$
		2.17	W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	17.4	mW/ $^\circ\text{C}$
		29	$^\circ\text{C}/\text{W}$
		12.3	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

- Notes: 5. For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.
 6. For a device surface mounted on FR4 PCB measured at $t \leq 10$ sec.
 7. Repetitive rating on 50mm x 50mm x 1.6mm FR4 PCB, $D=0.02$, pulse width=300 μs – pulse width limited by maximum junction temperature.
 8. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

Thermal characteristics


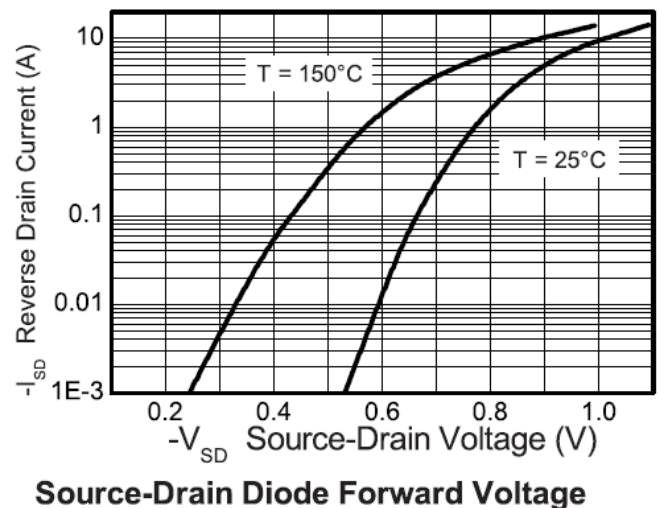
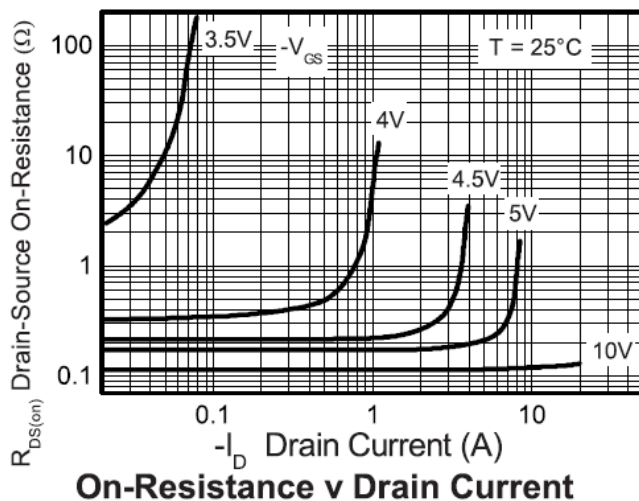
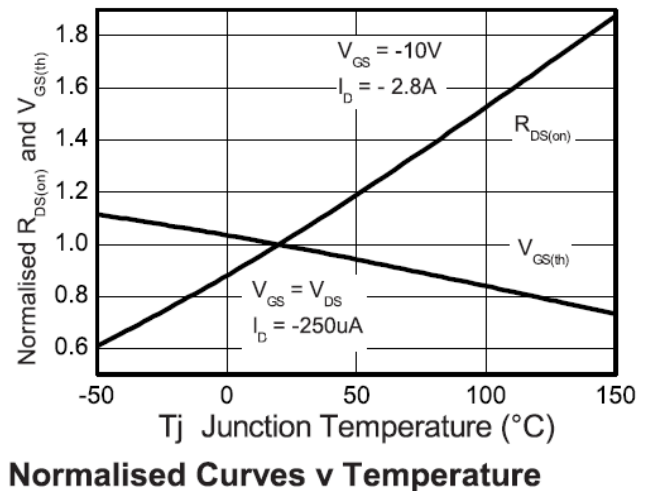
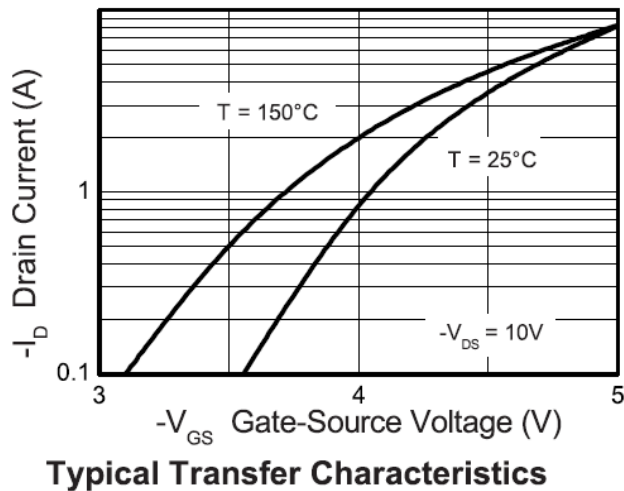
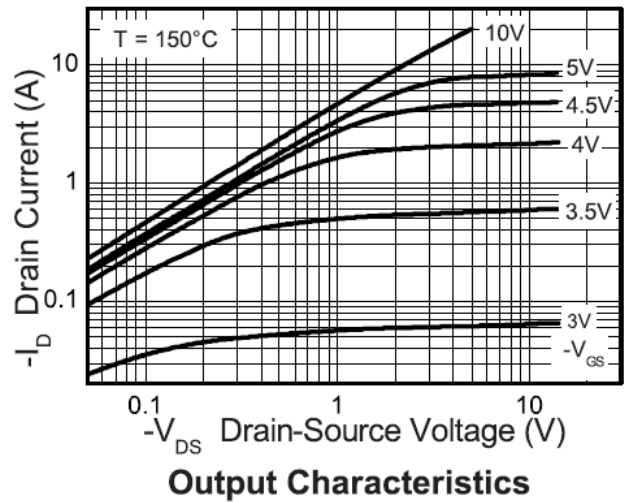
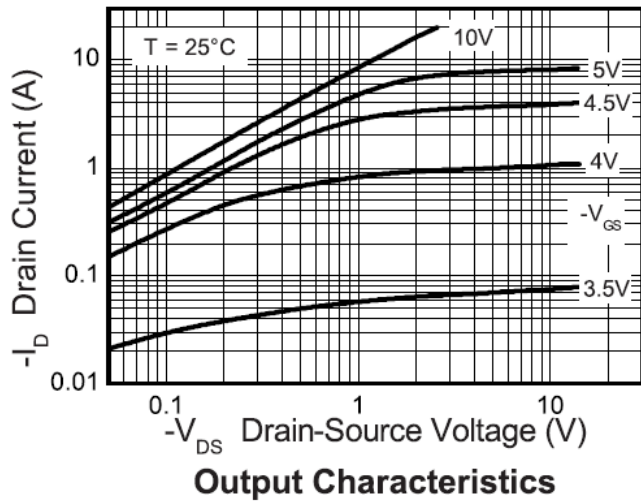


Electrical Characteristics (@ $T_A = +25^{\circ}\text{C}$, unless otherwise specified.)

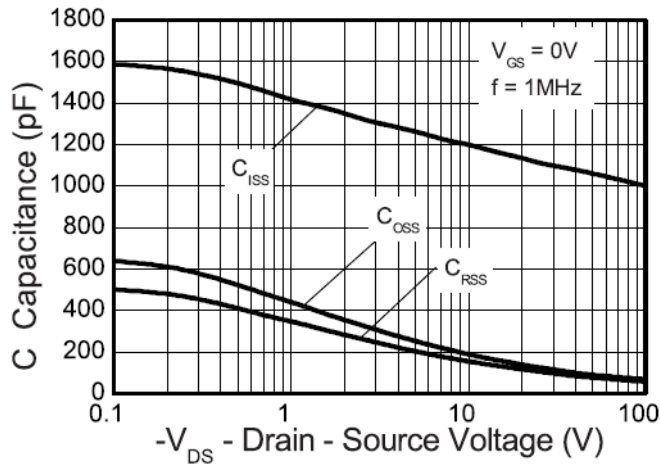
Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	-100	—	—	V	V _{GS} = 0V, I _D = -250μA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	-1	μA	V _{DS} = -100V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(th)}	-2	—	-4	V	V _{DS} = V _{GS} , I _D = -250μA
Static Drain-Source On-Resistance (Note 9)	R _{DS (ON)}	—	—	150 190	mΩ	V _{GS} = -10V, I _D = -2.8A V _{GS} = -6V, I _D = -2.4A
Forward Transconductance (Notes 9 & 11)	g _{fs}	—	6	—	S	V _{DS} = -15V, I _D = -2.8A
DYNAMIC CHARACTERISTICS (Note 11)						
Input Capacitance	C _{iss}	—	1055	—	pF	V _{DS} = -50V, V _{GS} = 0V, f = 1MHz
Output Capacitance	C _{oss}	—	90	—	pF	
Reverse Transfer Capacitance	C _{rss}	—	76	—	pF	
SWITCHING CHARACTERISTICS (Notes 10 & 11)						
Turn-On Delay Time	t _{d(on)}	—	4.9	—	ns	V _{DS} = -50V, V _{GS} = -10V, I _D = -1A, R _G = 6Ω
Rise Time	t _r	—	6.8	—		
Turn-Off Delay Time	t _{d(off)}	—	33.9	—		
Fall Time	t _f	—	17.9	—		
Total Gate Charge	Q _g	—	26.9	—	nC	V _{DS} = -50V, V _{GS} = -10V, I _D = -2.8A
Gate-Source Charge	Q _{gs}	—	3.9	—		
Gate-Drain Charge	Q _{gd}	—	10.2	—		
SOURCE-DRAIN DIODE CHARACTERISTICS						
Diode Forward Voltage (Note 9)	V _{SD}	—	-0.85	-0.95	V	T _J = +25°C , V _{GS} = 0V, I _S = -3.5A
Reverse Recovery Time (Note 11)	t _{rr}	—	49	—	ns	T _J = +25°C, I _S = -2.8A, di/dt=100A/μs,
Reverse Recovery Charge (Note 11)	Q _{rr}	—	107	—	nC	

Notes: 9. Measured under pulsed conditions. Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
 10. Switching characteristics are independent of operating junction temperature.
 11. For design aid only, not subject to production testing.

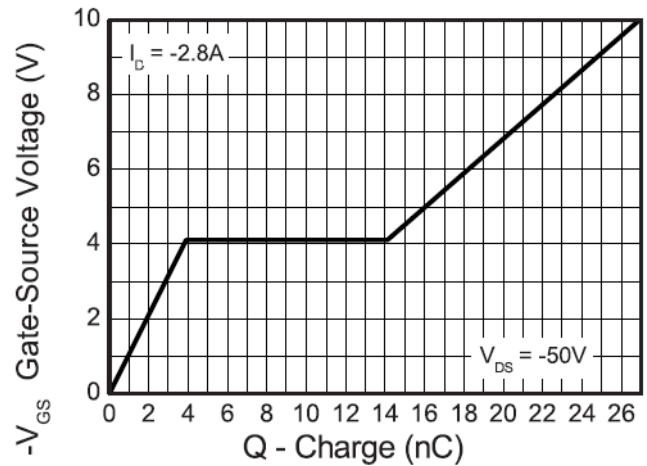
Typical characteristics



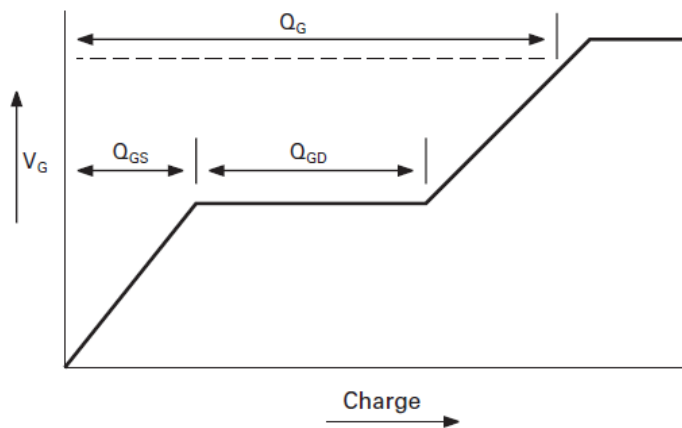
Typical characteristics



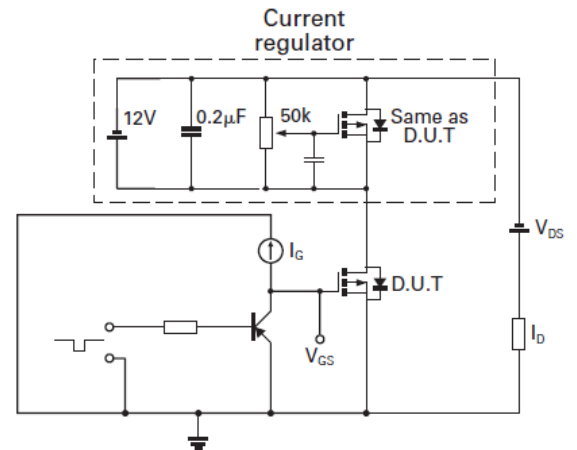
Capacitance v Drain-Source Voltage



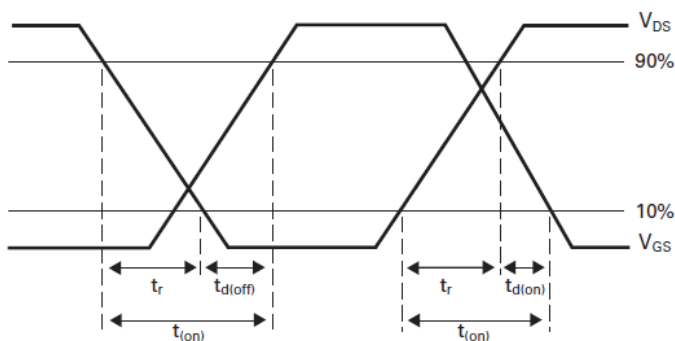
Gate-Source Voltage v Gate Charge



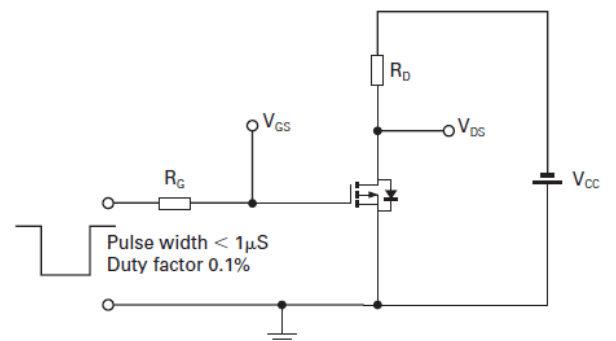
Basic gate charge waveform



Gate charge test circuit



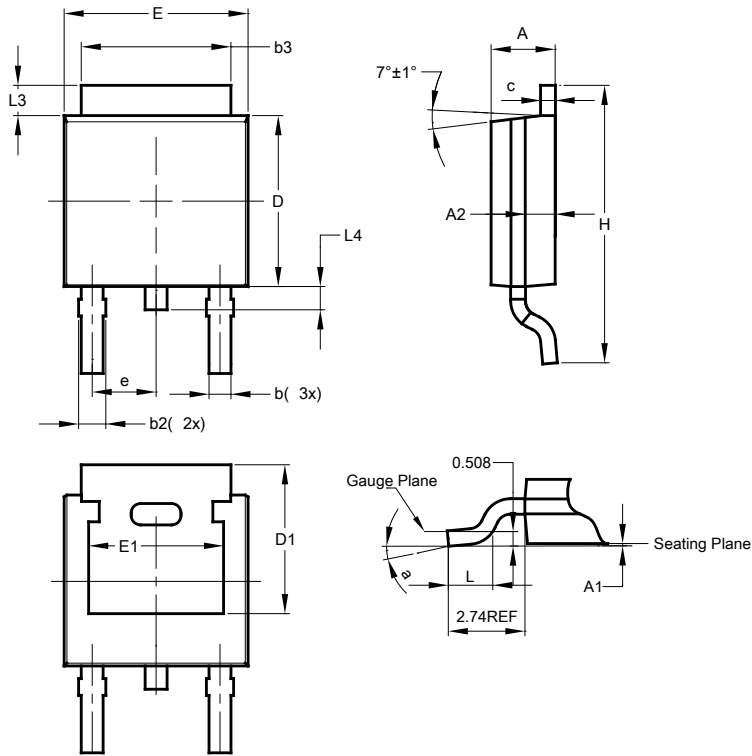
Switching time waveforms



Switching time test circuit

Package Outline Dimensions

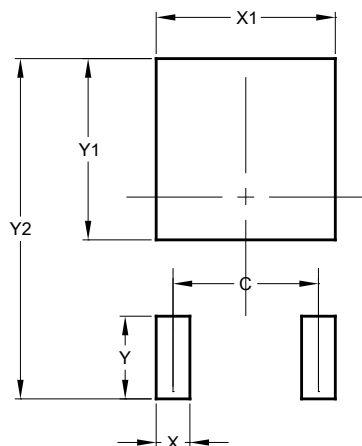
Please see AP02002 at <http://www.diodes.com/datasheets/ap02002.pdf> for latest version.



TO252 (DPAK)			
Dim	Min	Max	Typ
A	2.19	2.39	2.29
A1	0.00	0.13	0.08
A2	0.97	1.17	1.07
b	0.64	0.88	0.783
b2	0.76	1.14	0.95
b3	5.21	5.46	5.33
c	0.45	0.58	0.531
D	6.00	6.20	6.10
D1	5.21	-	-
e	-	-	2.286
E	6.45	6.70	6.58
E1	4.32	-	-
H	9.40	10.41	9.91
L	1.40	1.78	1.59
L3	0.88	1.27	1.08
L4	0.64	1.02	0.83
a	0°	10°	-
All Dimensions in mm			

Suggested Pad Layout

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for the latest version.



Dimensions	Value (in mm)
C	4.572
X	1.060
X1	5.632
Y	2.600
Y1	5.700
Y2	10.700

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